

| | | | | |
|-----------------------------------|--|---------------------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. 10/516,084 | Applicant(s)/Patent Under Reexamination BAST ET AL. | |
| | | Examiner Hoai-An D. Nguyen | Art Unit 2858 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|-----|--|-----------------|-------------------|----------------|
| * | A | US-5,355,734 A | 10-1994 | Kajino, Katsuhiro | 73/775 |
| * | B | US-4,255,974 A | 03-1981 | Dufrane et al. | 73/776 |
| * | C | US-4,484,132 A | 11-1984 | Crites, Nelson A. | 324/557 |
| D | US- | | | | |
| E | US- | | | | |
| F | US- | | | | |
| G | US- | | | | |
| H | US- | | | | |
| I | US- | | | | |
| J | US- | | | | |
| K | US- | | | | |
| L | US- | | | | |
| M | US- | | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|--|-----------------|---------|------|----------------|
| N | | | | | | |
| O | | | | | | |
| P | | | | | | |
| Q | | | | | | |
| R | | | | | | |
| S | | | | | | |
| T | | | | | | |

NON-PATENT DOCUMENTS

| | | | | | |
|---|---|---|--|--|--|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.